

Maximum Ratings (@ T_A = +25°C, unless otherwise specified.)

Characteristic	Symbol	Value	Units		
Drain-Source Voltage	V_{DSS}	-40	V		
Gate-Source Voltage			V_{GSS}	±25	V
Continuous Drain Current (Note 5) V _{GS} = -10V	Steady State	$T_C = +25$ °C $T_C = +70$ °C	I _D	-35 -27	Α
Continuous Drain Current (Note EVV - 40V	Steady State	$T_A = +25^{\circ}C$ $T_A = +70^{\circ}C$	I _D	-14 -11	Α
Continuous Drain Current (Note 5) V _{GS} = -10V	t<10s	$T_A = +25^{\circ}C$ $T_A = +70^{\circ}C$	I _D	-22 -18	Α
Pulsed Drain Current (10µs pulse, duty cycle = 1%)	I _{DM}	-100	Α		
Maximum Body Diode Forward Current (Note 5)	I _S	-5.5	Α		
Avalanche Current (Note 6)	I _{AS}	-57	Α		
Avalanche Energy (Note 6)			E _{AS}	162	mJ

Thermal Characteristics (@ T_A = +25°C, unless otherwise specified.)

Characteristic	_	Symbol	Value	Units
Total Dayor Dissination (Note 7)	T _A = +25°C	D-	3.5	W
Total Power Dissipation (Note 7)	$T_A = +70^{\circ}C$	P _D	2.2	
Thermal Desigtance, Junction to Ambient (Note 7)	Steady state	_	36	°C/W
Thermal Resistance, Junction to Ambient (Note 7)	t<10s	$R_{\theta JA}$	15	
Thermal Resistance, Junction to Case (Note 7)	Steady state	$R_{ heta JC}$	4.5	
Operating and Storage Temperature Range		$T_{J,}T_{STG}$	-55 to +150	°C

Electrical Characteristics (@ T_A = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition	
OFF CHARACTERISTICS (Note 7)							
Drain-Source Breakdown Voltage	BV_{DSS}	-40		_	V	$V_{GS} = 0V, I_D = -250\mu A$	
Zero Gate Voltage Drain Current	I _{DSS}	_	_	-1	μΑ	$V_{DS} = -40V, V_{GS} = 0V$	
Gate-Source Leakage	I _{GSS}	_	_	±100	nA	$V_{GS} = \pm 25V, V_{DS} = 0V$	
ON CHARACTERISTICS (Note 7)	ON CHARACTERISTICS (Note 7)						
Gate Threshold Voltage	$V_{GS(th)}$	-1.5	-2	-2.5	V	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	
Static Drain-Source On-Resistance	J	_	7	11	mΩ	$V_{GS} = -10V, I_D = -9.8A$	
Static Dialii-Source Off-Resistance	R _{DS(ON)}	_	9	15		$V_{GS} = -4.5V$, $I_D = -9.8A$	
Forward Transfer Admittance	Y _{fs}	_	26	_	S	$V_{DS} = -20V, I_{D} = -9.8A$	
Diode Forward Voltage	V_{SD}	_	-0.7	-1	V	$V_{GS} = 0V, I_{S} = -1A$	
DYNAMIC CHARACTERISTICS (Note 8)					-		
Input Capacitance	C _{iss}	_	4234	_		V _{DS} = -20V, V _{GS} = 0V f = 1MHz	
Output Capacitance	Coss	_	1036	_	pF		
Reverse Transfer Capacitance	C _{rss}	_	526	_			
Gate Resistance	R_{G}	_	7.77	_	Ω	$V_{DS} = 0V$, $V_{GS} = 0V$, $f = 1MHz$	
Total Gate Charge	Q_g	_	47.5	_		\\\ - 20\\ \\\ - 5\\	
Gate-Source Charge	Q_{gs}	_	14.2	_	nC	$V_{DS} = -20V, V_{GS} = -5V$ $I_{D} = -9.8A$	
Gate-Drain Charge	Q_{gd}	_	13.5	_			
Turn-On Delay Time	$t_{D(on)}$	_	13.2	_		V_{GS} = -10V, V_{DD} = -20V, R_{G} = 6 Ω , I_{D} = -1A	
Turn-On Rise Time	t _r	_	10	_	no		
Turn-Off Delay Time	$t_{D(off)}$	_	302.7		ns		
Turn-Off Fall Time	t _f	_	137.9	_			

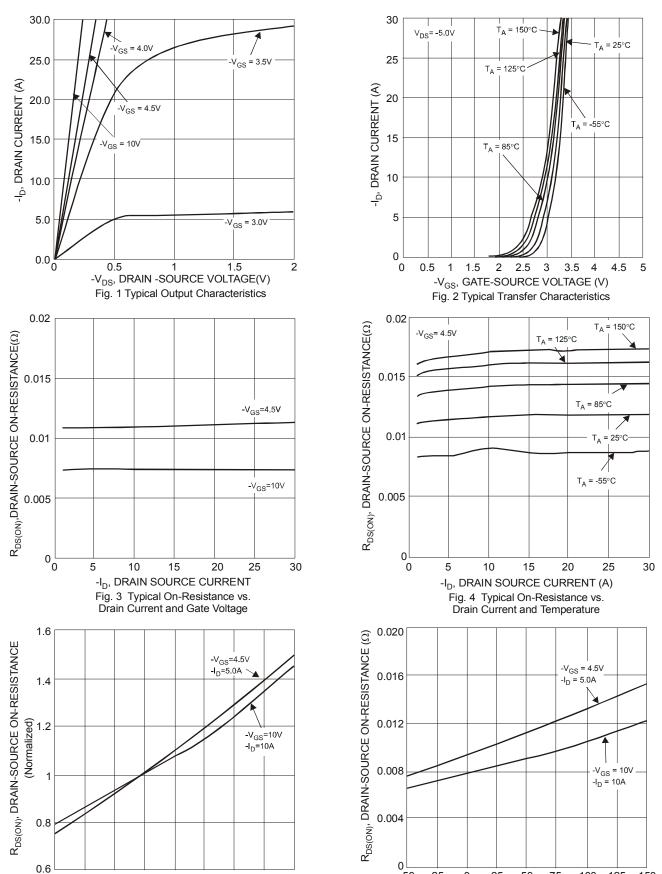
5. Device mounted on FR-4 substrate PC board, 2oz copper, with thermal bias to bottom layer 1inch square copper plate.

6. UIS in production with L = 0.1mH, T_J = +25°C.

7. Short duration pulse test used to minimize self-heating effect.

8. Guaranteed by design. Not subject to production testing. Notes:





-50

-25

75

100

125

50

T_J, JUNCTION TEMPERATURE (°C)

Fig. 5 On-Resistance Variation with Temperature

25

-50

-25

0

25

50

T_{.I}, JUNCTION TEMPERATURE (°C)

Fig. 6 On-Resistance Variation with Temperature

75

100 125

150



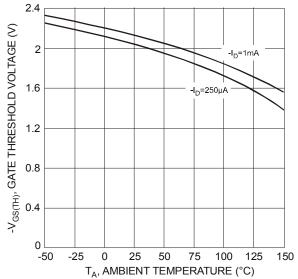
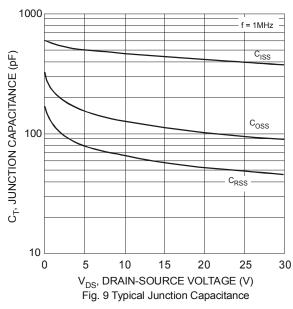
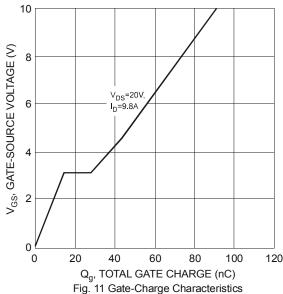
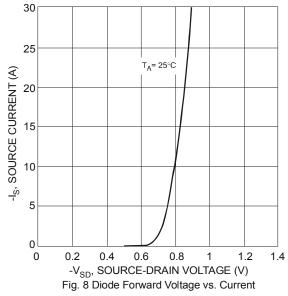


Fig. 7 Gate Threshold Variation vs. Ambient Temperature







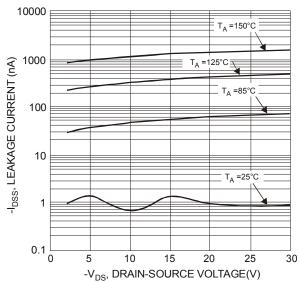


Fig. 10 Typical Drain-Source Leakage Current vs. Voltage

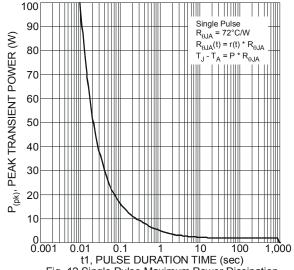
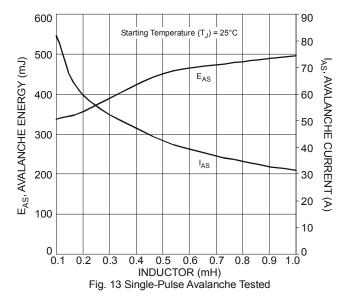
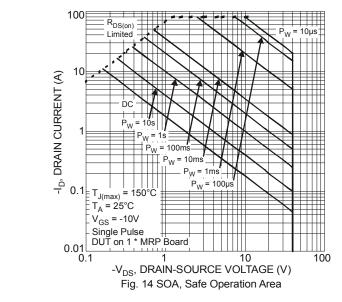
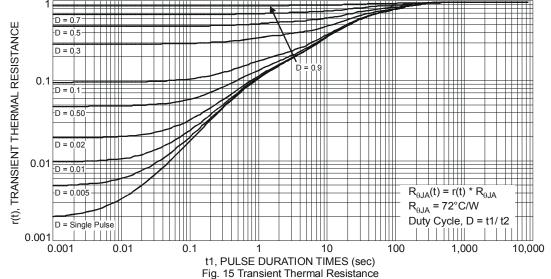


Fig. 12 Single Pulse Maximum Power Dissipation





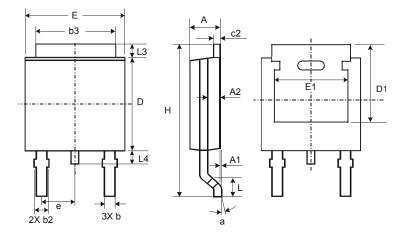






Package Outline Dimensions

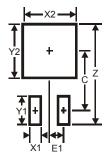
Please see AP02002 at http://www.diodes.com/datasheets/ap02002.pdf for the latest version.



TO252						
Dim	Min	Max	Тур			
Α	2.19	2.39	2.29			
A 1	0.00	0.13	0.08			
A2	0.97	1.17	1.07			
b	0.64	0.88	0.783			
b2	0.76	1.14	0.95			
b3	5.21	5.46	5.33			
c2	0.45	0.58	0.531			
D	6.00	6.20	6.10			
D1	5.21	_	_			
е	_	_	2.286			
Е	6.45	6.70	6.58			
E1	4.32	_	_			
Н	9.40	10.41	9.91			
L	1.40	1.78	1.59			
L3	0.88	1.27	1.08			
L4	0.64	1.02	0.83			
а	0°	10°	_			
All Dimensions in mm						

Suggested Pad Layout

Please see AP02001 at http://www.diodes.com/datasheets/ap02001.pdf for the latest version.



Dimensions	Value (in mm)
Z	11.6
X1	1.5
X2	7.0
Y1	2.5
Y2	7.0
С	6.9
E1	2.3



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